

Search Notes	Application/Control No.	Applicant(s)/Patent Under Reexamination
	10550009	CHEN ET AL.
	Examiner	Art Unit
	KAMRAN AFSHAR	2617

SEARCHED

Class	Subclass	Date	Examiner
455	450-453, 422.1-425, 428, 445, 560-561, 550.1, 517	9/16/2007	KA
370	328, 338, 395.1, 395.52, 351-356, 401, 386	9/16/2007	KA

SEARCH NOTES

Search Notes	Date	Examiner
East Search (US-PGPUB; USPAT; EPO; DERWENT; IBM TDB)	9/16/2007	KA
William Trost	9/16/2007	KA
Ferris Derric	10/22/2007	KA
George Eng, Charls Appiah (Double patenting)	10/22/2007	KA
Updated East Search	12/11/2007	KA
Updated East Search	4/22/2008	KA
John Peng, 101 and new matter	4/22/2008	KA
John Peng, 101 and new matter	11/6/2008	KA
Updated East Search	11/10/2008	KA
Updated East Search	1/16/2009	KA
George Eng, New Matter	1/16/2009	KA

INTERFERENCE SEARCH

Class	Subclass	Date	Examiner

	/K. A./ Primary Examiner.Art Unit 2617
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